

# Shintake Monitor in ATF2 : Present Status

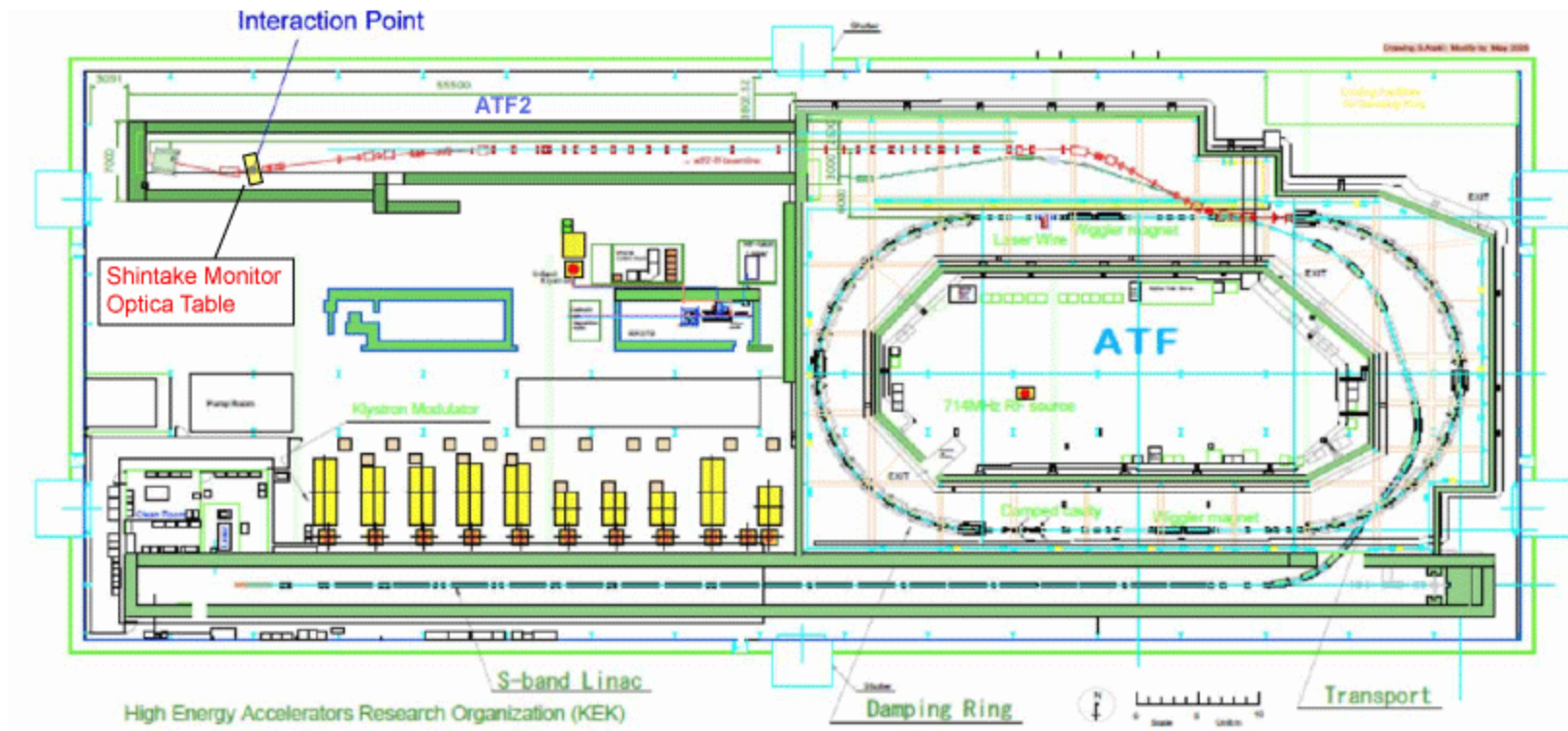
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# ATF/ATF2

## ATF

- accelerate electron beam to 1.3 GeV
- normalized  $\gamma\epsilon_y = 2.8 \times 10^{-8} \text{ m} \cdot \text{rad}$  achieved in the Damping Ring

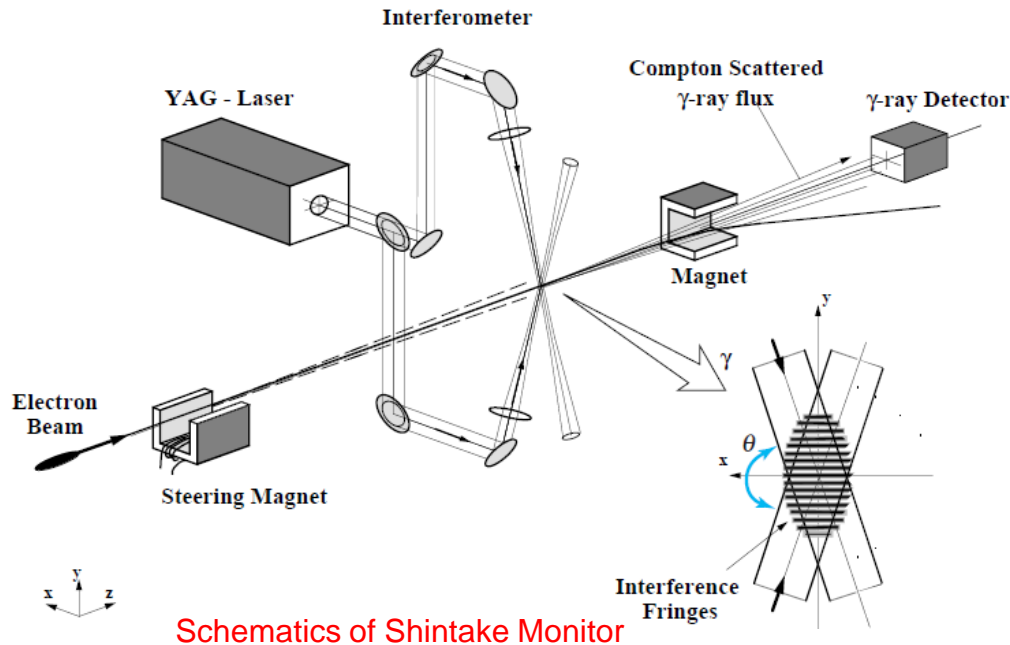


## Goals of ATF2

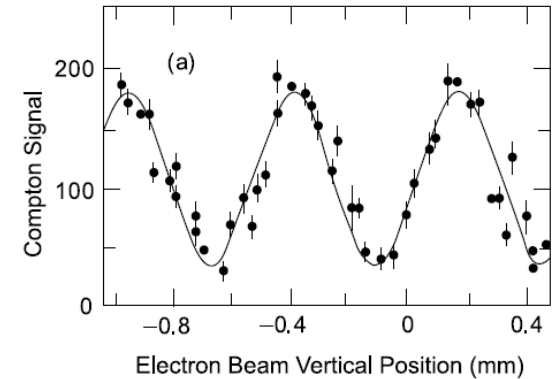
- focus the vertical beam size to 37 nm
- stabilize the vertical beam position in 2 nm resolution

## Layout of ATF/ATF2

# Principle of Laser Interference Beam Size Monitor (Shintake Monitor)



Schematics of Shintake Monitor



Measured signal in FFTB at SLAC  
T. Shintake *et al.*, 1992  
 $\sigma_y \sim 65$  nm beam size was measured

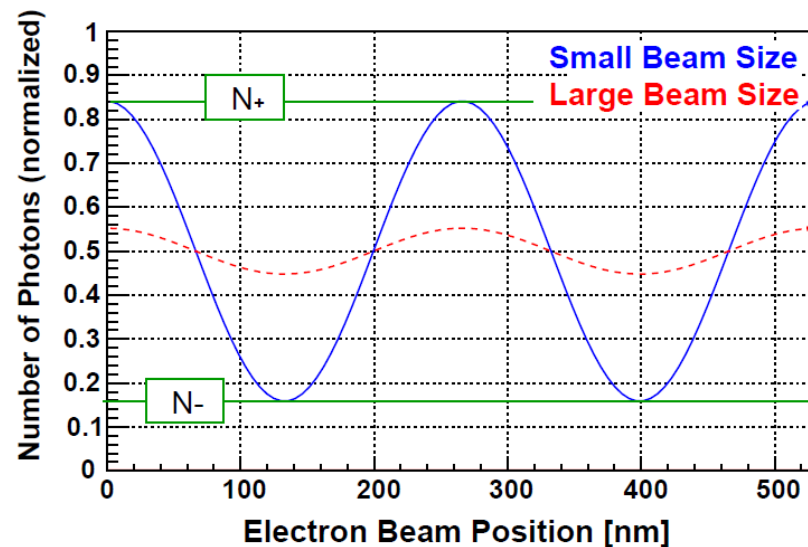
Modulation depth

$$M \equiv \left| \frac{N_+ - N_-}{N_+ + N_-} \right| = \frac{\text{Amplitude}}{\text{Average}}$$

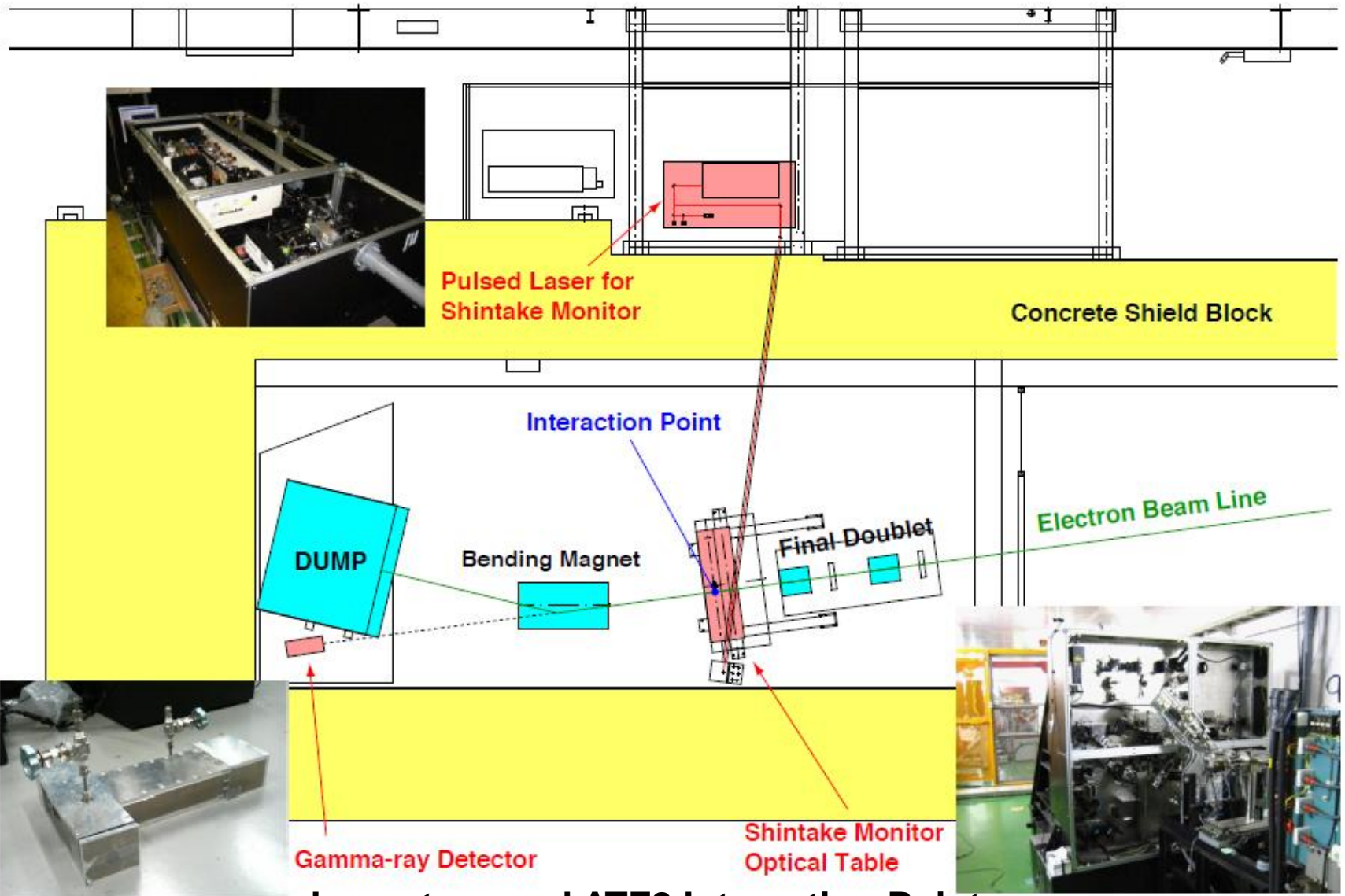
Beam Size

$$\sigma_y = \frac{d}{2\pi} \sqrt{2 \log \left( \frac{|\cos \theta|}{M} \right)}$$

$d$ : fringe pitch     $\theta$ : crossing angle



# Components of Shintake Monitor



Layout around ATF2 Interaction Point

# Laser System



## Q-switched Nd:YAG Laser (wave length:1064 nm) PRO350 (SpectraPhysics)

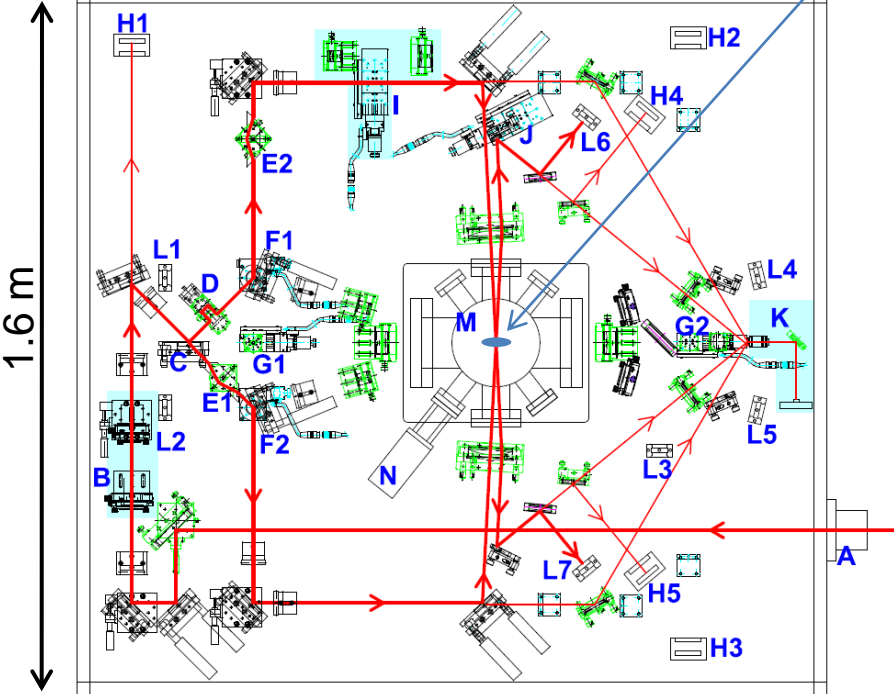
Specifications	Value
Wave length (second harmonics)	532 nm
Line width	$< 0.003 \text{ cm}^{-1}$
Repetition rate	6.25 Hz
Pulse width	8 ns (FWHM)
Timing jitter	$< 1 \text{ ns (RMS)}$
Pulse energy	1.4 J/pulse

- To make smaller interference fringe, small wave length is needed.  
second harmonics 532nm
- High power laser is needed to raise S/N ratio.  
1.4J/pulse

# Vertical Optical Table

Electron Beam

1.7 m



Laser path diagram (174 deg crossing angle)

Picture of the vertical optical table installed at ATF2 beam line

# Switch of Laser Crossing Angle

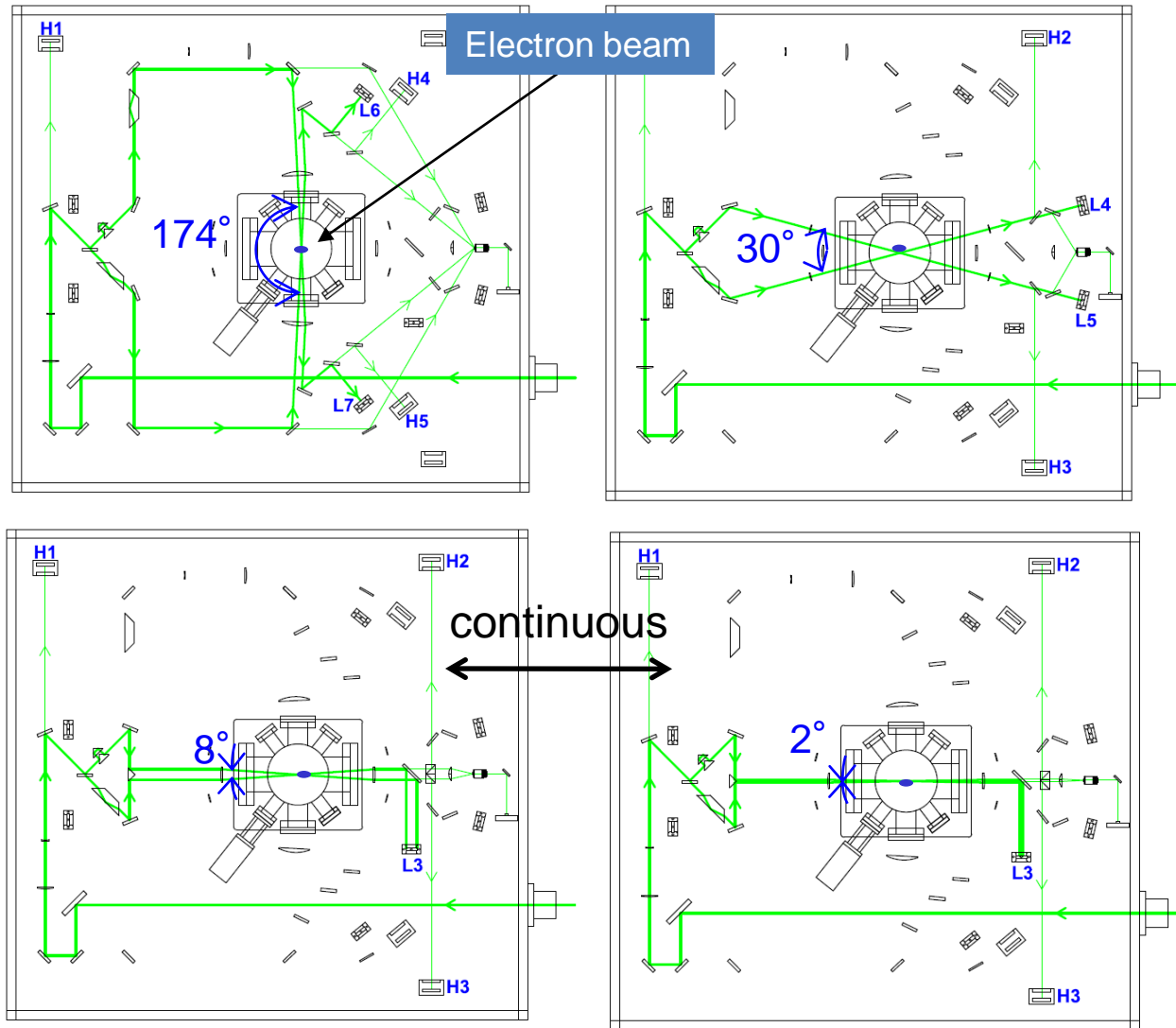
Issue of the Shintake Monitor  
 ⇒ measurable beam size range is limited  
 (7 – 40 % of fringe pitch),  
 if the fringe pitch is fixed.



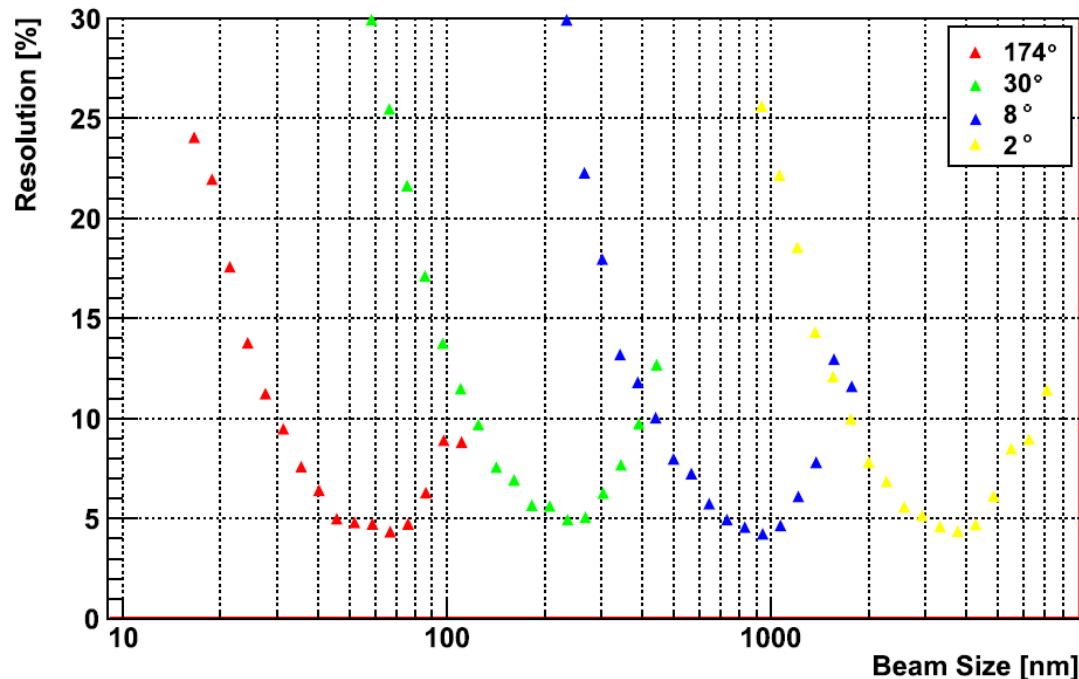
By changing the laser crossing angle,  
 the measurable beam size range  
 can be enlarged.

fringe pitch  $d = \frac{\lambda}{\sin \frac{\theta}{2}}$

$\theta$ : crossing angle



# Expected Beam Size Resolution



## Simulation condition

- Statistical error of the Compton scattered photons (including background subtraction): 10%
- Electron beam position jitter: 30 % of beam size
- Jitter of interference fringe phase: 400 mrad
- Jitter of laser pulse energy: 6.8%
- 1 measurement time : 1 min.

◆ Expected resolution (statistical error) is evaluated by simulation considering the probable error sources

◇ in 25 nm ~ 6 μm range  
 : less than 12 %

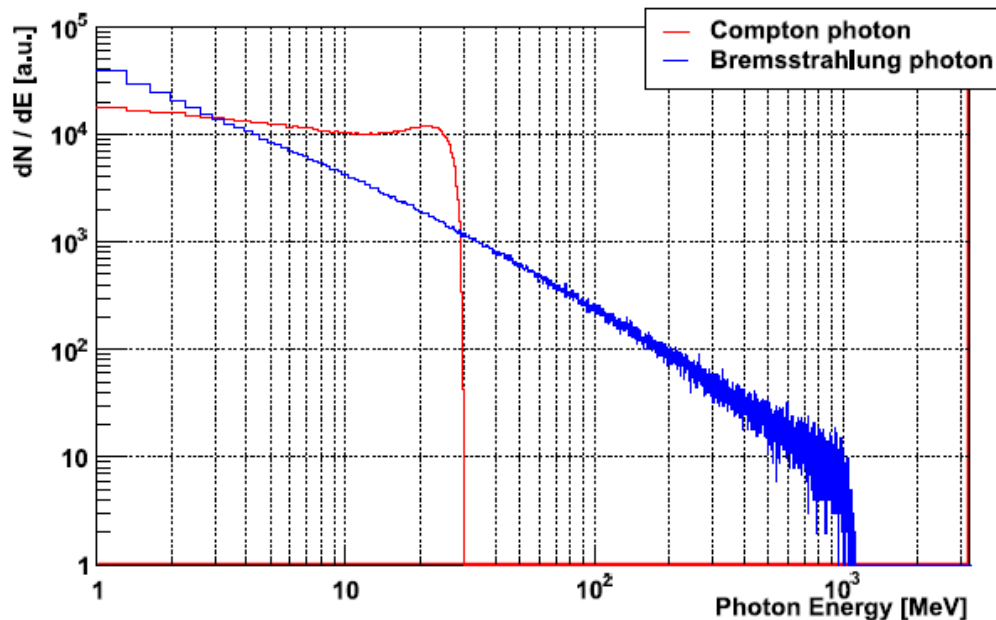
◆ Systematic error also need to be evaluated.

	174°	30°	8°	2°
Fringe pitch	266 nm	1.03 μm	3.81 μm	15.2 μm
Minimum	25 nm	100 nm	360 nm	-
Maximum	100 nm	360 nm	-	6 μm



# Detection of Compton Scattered Photons

- Difficulty at ATF
  - Background photons have higher energy than the signal photons (Compton scattered photons).



Simulated Gamma-ray Energy Spectrum

## ◆ Signal

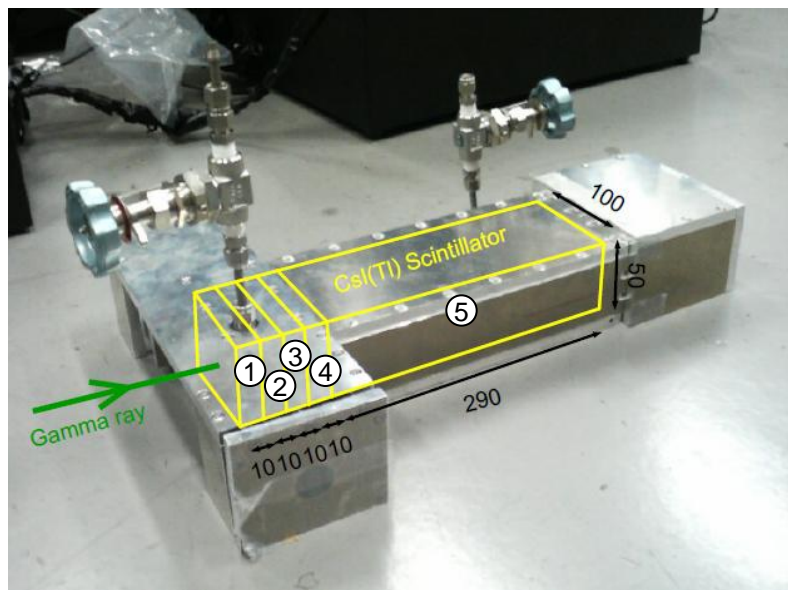
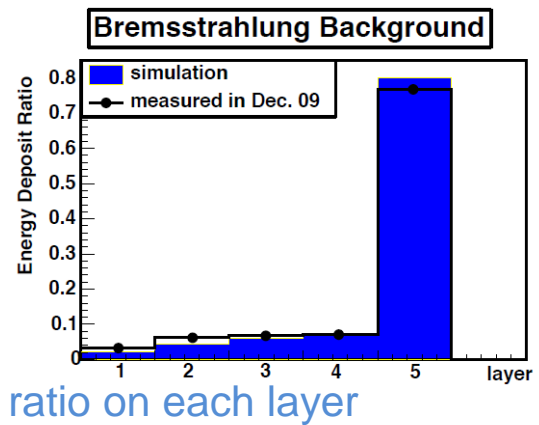
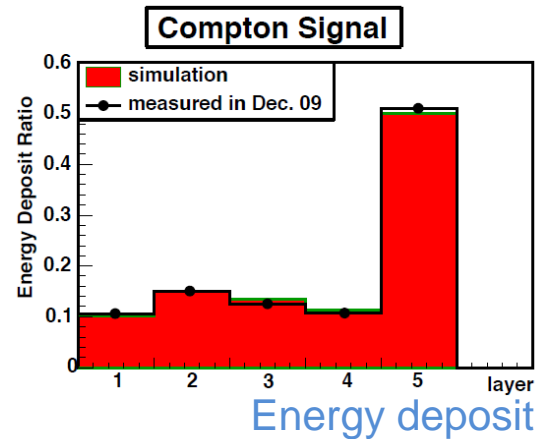
- ◇ Compton scattered photons
- ◇ Compton edge at 30 MeV
- 1.3 GeV electron vs. 532nm (2.3 eV) photons

## ◆ Background

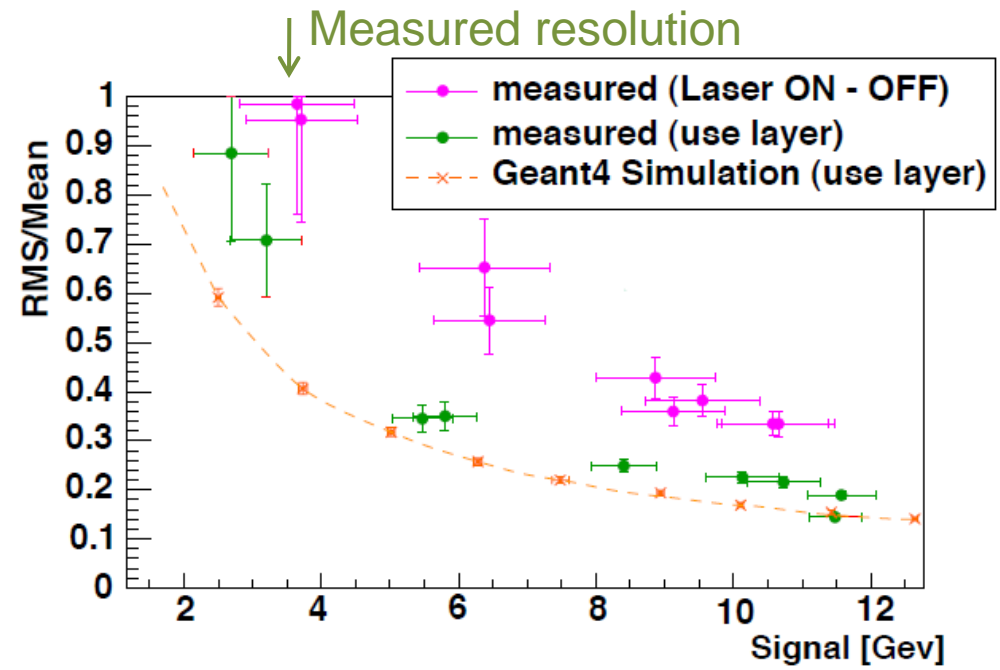
- ◇ Bremsstrahlung
- ◇ Broad spectrum from 1.3 GeV (energy of electron beam)

# Gamma-ray Detector

- Use multi-layered calorimeter
  - CsI(Tl), 4 thin layers + 1 bulk
- Calculate the amount of Compton signal and the background using the difference of energy deposit on each layer.

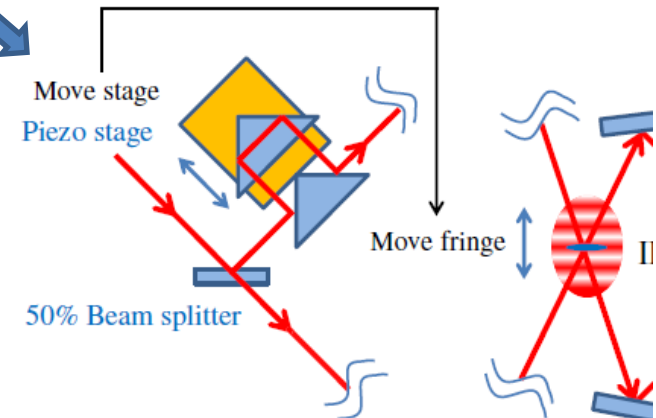
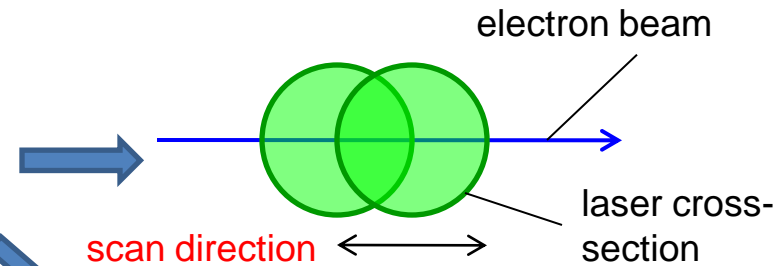
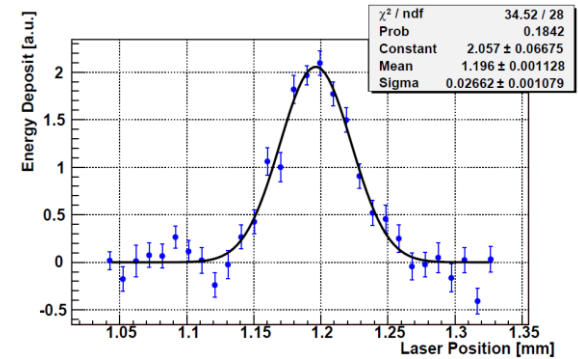


Multi layered gamma-ray detector

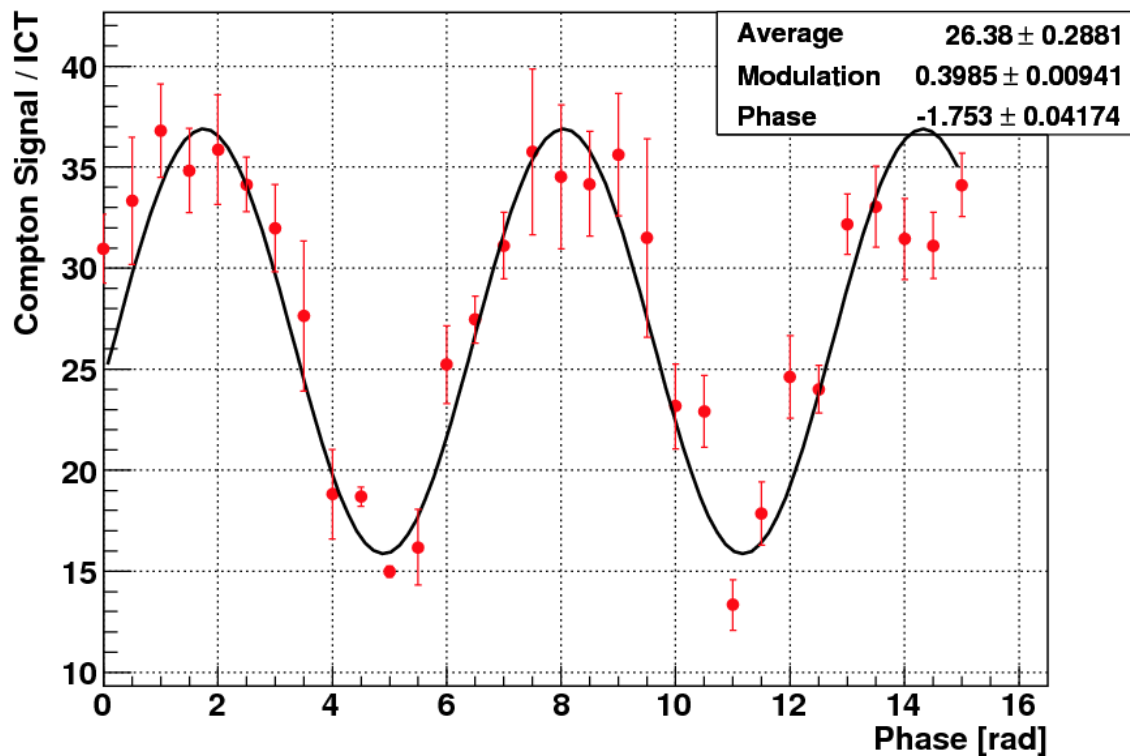


# Measurement Procedure

1. Adjust the laser pulse and the electron beam timing
2. Scan the laser beam perpendicular to the electron beam axis
  - Then move two laser beams to the Compton signal peak position
3. Scan one laser beam in the electron beam axis and scan the laser phase
  - search the maximum interfering position
  - The present beam size is obtained from this maximum modulation depth
4. Then repeat the beam tuning and the beam size measurement



# Measurement Result



Example of the measurement  
(measured on 25 Feb. 2010)

## Beam condition

- $\beta_x^* \sim 4$  cm (setting)
- $\beta_y^* \sim 1$  mm (setting)
- $\sigma_x^* \sim 10$   $\mu\text{m}$  (measured)

## Measurement condition

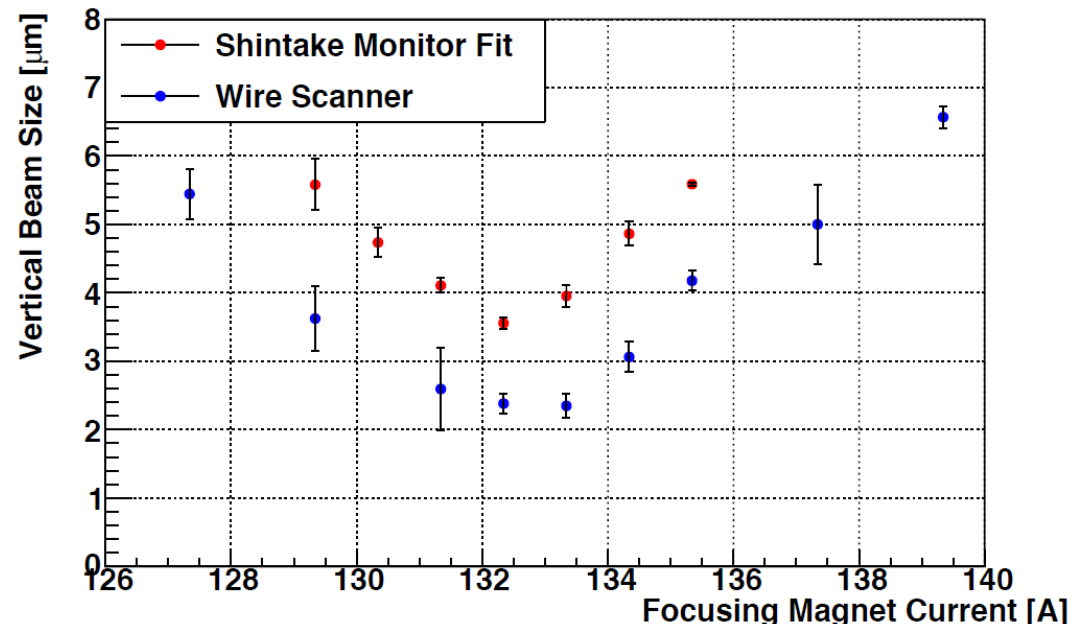
- Crossing angle  $\sim 2.75$  deg  
= fringe pitch  $\sim 11$   $\mu\text{m}$

measured  $\sigma_y^* \sim 2.4$   $\mu\text{m}$

# Systematic Error

- At the IP, another beam size monitor (wire scanner) is installed
  - 10  $\mu\text{m}$  diameter tungsten wire
  - resolution limit is 2.5  $\mu\text{m}$
- Compared the Shintake monitor and the wire scanner measurement results
  - measurement was done by changing the final focusing magnet current
  - Systematic difference was observed between two measurements

Correction of the systematic errors  
will be explained in next talk



# Summary and Near Future Plan

- Succeeded in the measurement of several  $\mu\text{m}$  beam size by using the Shintake Monitor in ATF2
- Laser optics is ready for all measurement ranges.
- The current beam time will be continued until June
  - Next beam time will be started in October
- Before the summer shutdown, aim to measure  $\sim 100$  nm beam size

Schedule	2010												2011						
	Jan	Feb	Mar	Apr	May	Jun	Jul	Aug	Sep	Oct	Nov	Dec	Jan	Feb	May	Apr	Jun		
ATF Beam Operation	■												■						
Measurement of $< 1\mu\text{m}$ beam size	■																		
Measurement of $\sim 100$ nm beam size					■								■						
Measurement of 37 nm beam size											■								
Stabilization of 37 nm beam size												■							

# Backup

# Adjustment of Laser Position

- To adjust the laser beam position to the electron beam initially, screen monitors are used
- Check the laser beams and the electron beam image on the screen
- Adjustment of several 10  $\mu\text{m}$  resolution is possible.

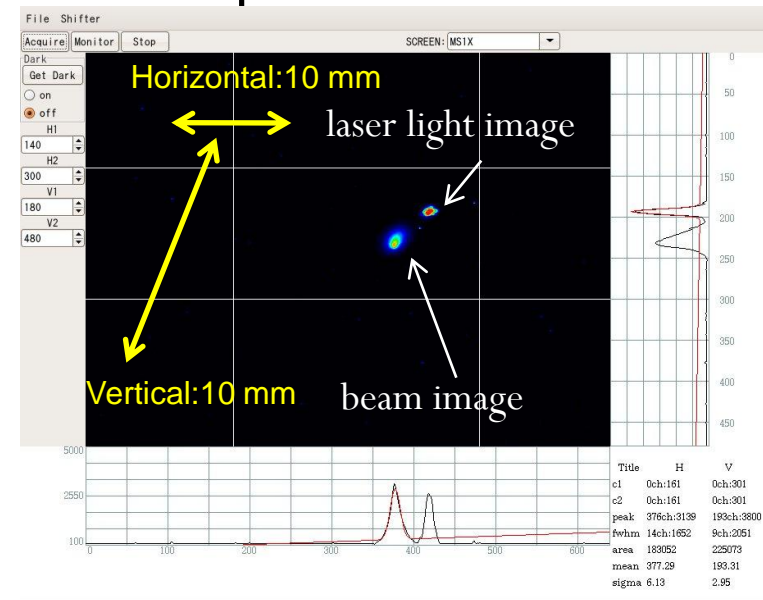
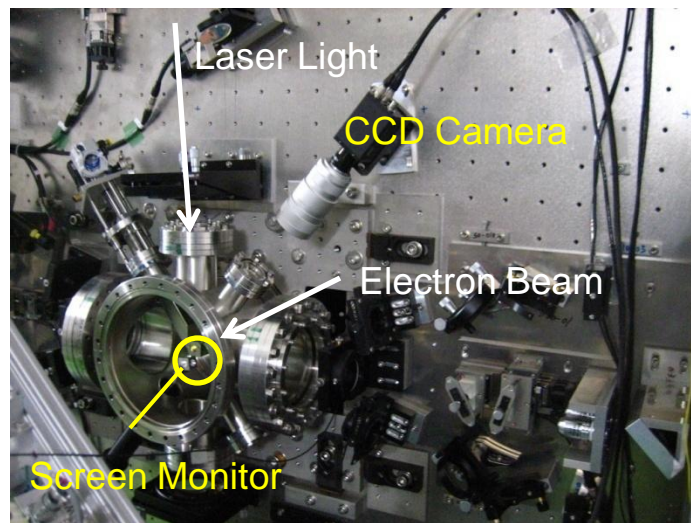


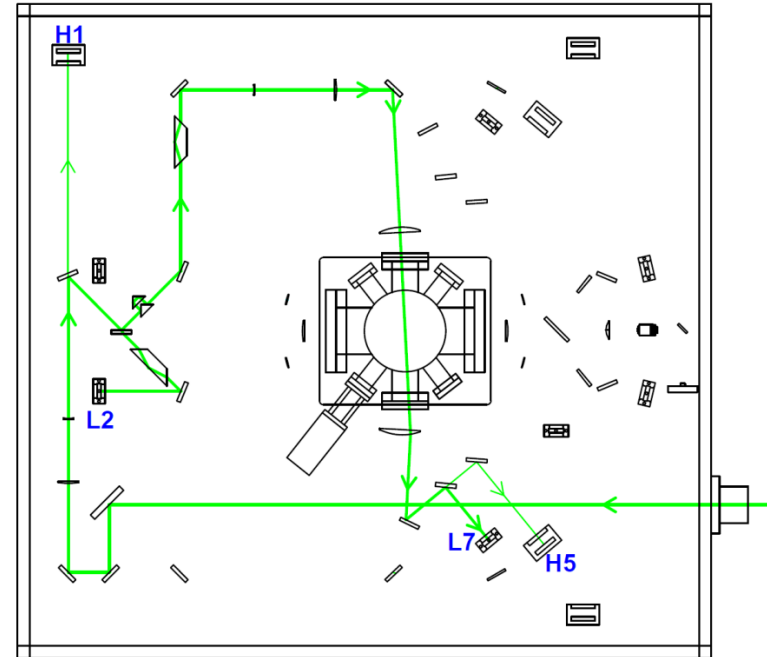
Image of screen monitor



# Measurement of Horizontal Beam Size

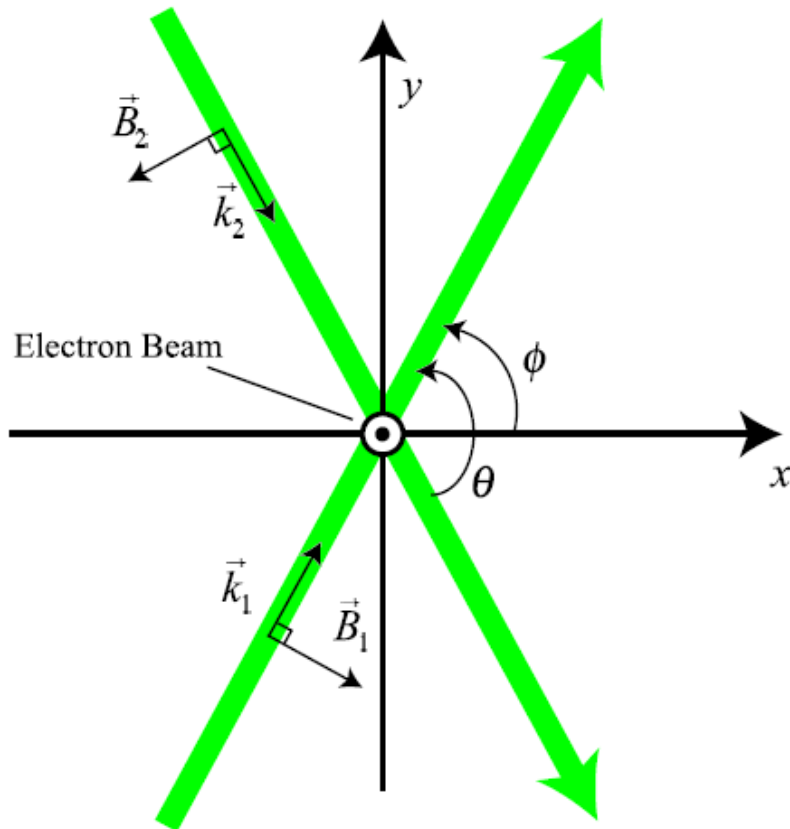
- For the horizontal beam size measurement, 2 types of measurement are possible.
  - Tungsten wire scanner
    - uses 10  $\mu\text{m}$  diameter
    - 2.5  $\mu\text{m}$  beam size measurement is possible
  - Laser wire
    - Designed laser width at the IP is  $\sigma_x = 5 \mu\text{m}$
- Designed horizontal beam size at the IP of ATF2

$$\sigma_x^* = 2.8 \mu\text{m}$$



Laser Path for horizontal beam size measurement

# Calculation of Beam Size



Change of Compton photon signal

$$N_\gamma(y_0) = \frac{N_0}{2} \left\{ 1 + \cos 2k_y y_0 \cos \theta \exp \left[ \underbrace{-2(k_y \sigma_y)^2}_{M} \right] \right\}$$

$y_0$  : position of e- beam

$$M \equiv \left| \frac{N_+ - N_-}{N_+ + N_-} \right| = \frac{\text{Amplitude}}{\text{Average}}$$

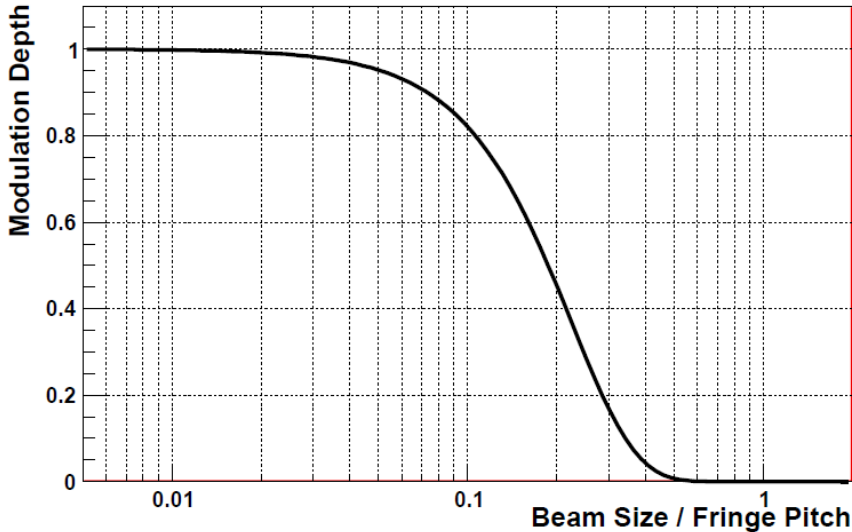
Beam Size

$$\sigma_y = \frac{d}{2\pi} \sqrt{2 \log \left( \frac{|\cos \theta|}{M} \right)}$$

Interference fringe pitch

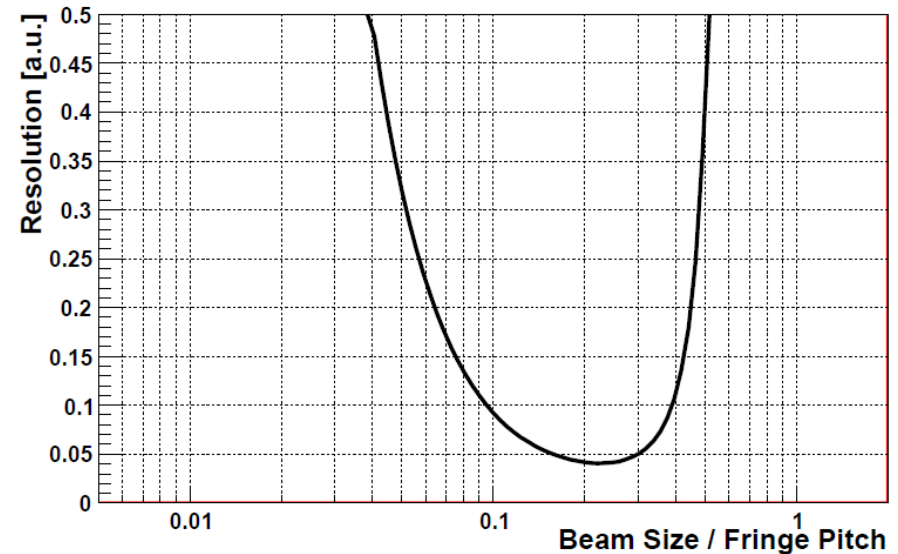
$$d = \frac{\lambda}{2 \sin \phi}$$

# Estimation of Measurement Resolution



Relationship between the modulation depth:  $M$  and beam size

- Beam size large  $\rightarrow M \approx 0$
- Beam size small  $\rightarrow M \approx 1$
- there exists measurable range according to each fringe pitch



Relationship between the measurement resolution and beam size (assume  $\Delta M = \text{const.}$ )

- The best resolution is obtained at around the 20% of the fringe pitch

# Interaction of Electromagnetic Field and Electron

- Electromagnetic field in electron rest frame (with \*)
- Electromagnetic field in laboratory frame (wo \*)

$$\begin{cases} \mathcal{E}_x^* &= \gamma(\mathcal{E}_x - \beta B_y) \\ \mathcal{E}_y^* &= \gamma(\mathcal{E}_y + \beta B_x) \\ \mathcal{E}_z^* &= \mathcal{E}_z \end{cases} ,$$

$$\begin{cases} B_x^* &= \gamma(B_x + \beta \mathcal{E}_y) \\ B_y^* &= \gamma(B_y - \beta \mathcal{E}_x) \\ B_z^* &= B_z \end{cases} ,$$

- $\gamma$ -factor : 2544 @ 1.3GeV electron

- Modulation depth @ 5.7 nm ILC beam
  - 89.6% with 157 nm F2 laser
  - 92.9% with 193 nm Excimer laser
  - 93.9% with 213 nm YAG 5<sup>th</sup> laser

In current error factors (ATF2), 17% resolution at M=90%
- Multi bunch operation
  - Quick accumulation of statistics
    - Improvement of resolution by a factor of 10 at 3940 bunches
  - 1 train measurement – slow drift suppressed
  - **Need high-repetition laser**
  - Fast phase scan by a Pockels cell
- Systematic error is similar, 5% can be achieved

# Shintake monitor for the ILC (2)

- Installation at the Interaction Point in the beam commissioning stage
  - Assure 5.7 nm beam focusing
  - Fast tuning without interaction
  - Must be removed when installing the detectors
    - By push-pull structure??
- Installation to the second IP for a diagnostic monitor
  - $> 25$  nm beam size measurements are much more realistic using current scheme.

# Experiment at ATF2

- Experiment at ATF2 with 37 nm beam size can be the test for ILC 5.7 nm beam size?
- Vertical beam size is given as follows,
  - $\beta_y$  :  $\beta$ -function (determined by the strength of the focusing magnet)
  - $\varepsilon_{n,y}$  : normalized vertical emittance (determined by the performance of the damping ring)
  - $\gamma$  :  $\gamma$ -factor of the accelerated beam
- Therefore, if the same  $\beta$  and emittance will be obtained with the ILC beam, 5.7 nm focusing is possible with the ATF2 beam optics

$$\sigma_y = \sqrt{\frac{\beta_y \varepsilon_{n,y}}{\gamma}}$$

	ATF2	ILC
beam energy	1.3 GeV	250 GeV
$\gamma$ for electron	2544	$4.89 \times 10^5$
$1/\gamma$	$3.9 \times 10^{-4}$	$2.0 \times 10^{-6}$